

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

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Applicant:

YAMAGUCHI et al.

Filing Date:

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Group Art Unit:

2811

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
						Yes No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

DOMEN et al., "Optical gain in GaN Based Semiconductors", VERTICAL-CAVITY LASERS, TECHNOLOGIES FOR A GLOBAL INFORMATION INFRASTRUCTURE, WDM COMPONENTS TECHNOLOGY, ADVANCED SEMICONDUCTOR LASERS AND APPLICATIONS, GALLIUM NITRIDE MATERIALS, PROCESSING, AND DEVICES, 1997 DIGEST OF THE IEEE/LEOS SUMMER TOPICAL M, August 11, 1997, pp. 35-36, XP010243183

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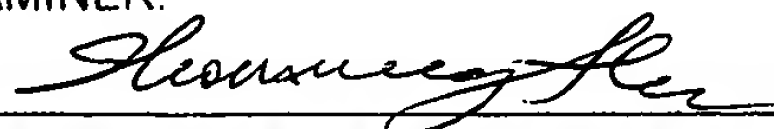
BINET et al., "Optical pumping in nitride cavities with etched mirror facets", MATERIALS SCIENCE AND ENGINEERING B, ELSEVIER SEQUOIA, LAUSANNE, CH, December 18, 1997, pp. 183-187, XP004119130

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EXAMINER:



DATE CONSIDERED

12/20/04

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* English language abstract provided for the Examiner's convenience